

IC Electron-Lens Beam Profile Monitoring

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Abstract

(YAG offset 2°)

LED Ring Illumination

Increased detail on YAG

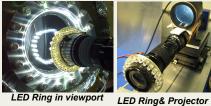
Beam profile measurements are ongoing of a 15keV electron beam, destined for an Electron Lens to be installed in RHIC this year. Two methods of profile measurements are compared. A pin-hole masked faraday cup collects charge from the beam pulses as the beam is raster scanned over it, developing a matrix of intensity measurements that are compared to a digital camera image of a YAG crystal.





View upstream into collector

Illumination Techniques



LED Ring in viewport



LED Ring Illumination Mirror polished surface of YAG reflects illumination

Projected LED Illumination

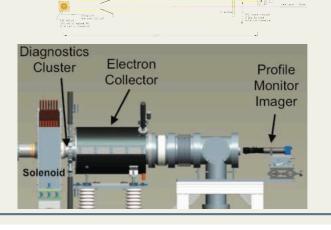
On the Lens

With Loom



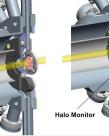
Projected LED Illumination Increased detail on bezel





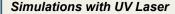
YAG Screen & Pinhole Faraday Cup Two cutaway views of

same diagnostics cluster upstream of collector showing segmented Halo Monitor (dark gray), YAG Screen (left, insert position), Pin Hole detector (right, inserted).

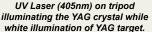


YAG & Camera Details

- Electron beam profile measurements will be made with a 30mm diameter, 0.1mm YAG:Ce screen from Crytur, Ltd. The expected beam diameter is ~10mm.
- Crystals are coated at BNL with 100nm of graphite. We will compare to an aluminium coated crystal for image performance, lifetime, and for backscattering electrons
- The electron beam power deposited on the screen will be limited to avoid damage.
- Screen images will be acquired using a AVT Manta G-145B 2/3" CCD camera (GigE), and zoom lens from Navitar, mounted 1.2m downstream of the YAG.





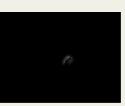




bench test



+ Laser On "scratch" Laser on YAG during



Laser only on "scratch" -> Not in YAG

